

# **Precision investigation of modern crystalline material Niobium Carbide by diffraction methods**

**FRANK LABORATORY OF NEUTRON PHYSICS**

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**SPOTOSE Libo**

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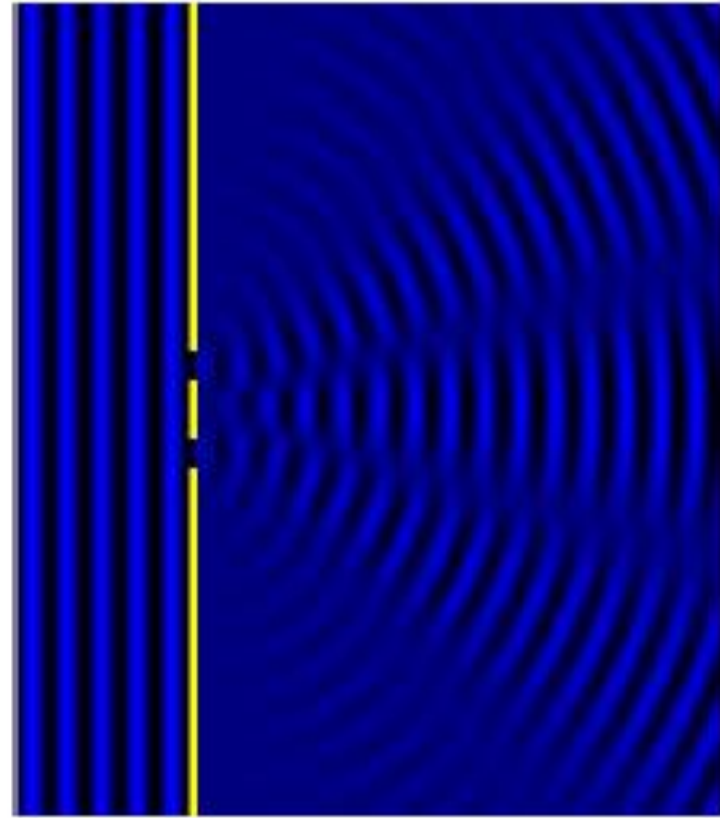
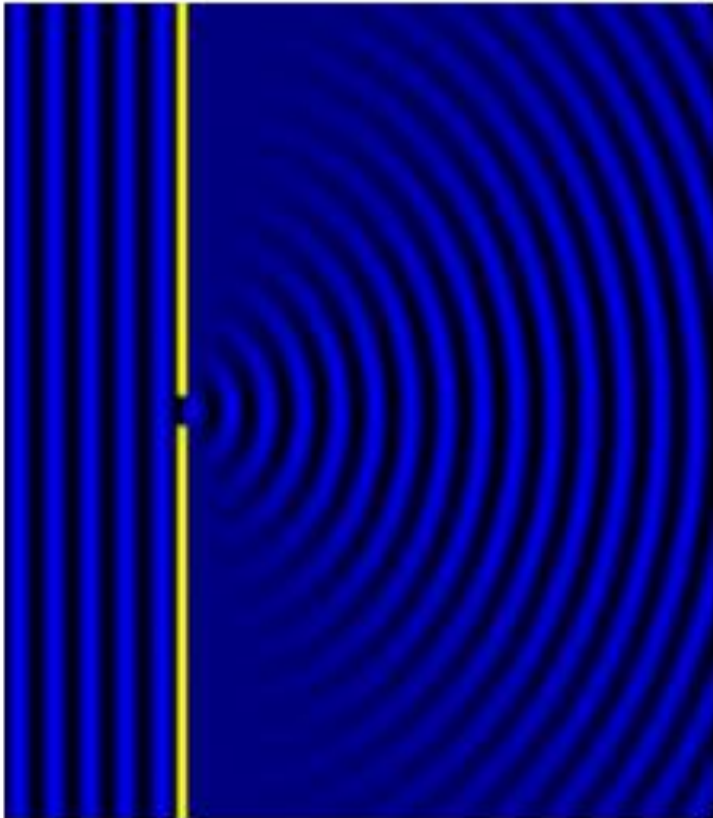
# PART I BASICS OF DIFFRACTION

SPOTOSE LIBO



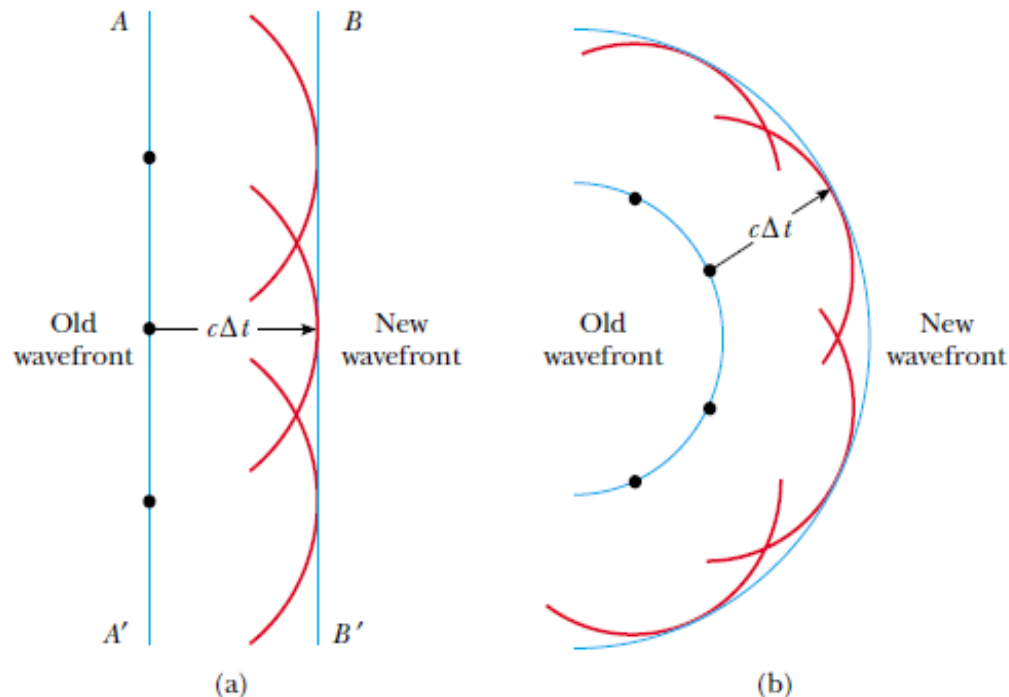
# Diffraction

The bending of waves after passing around small apertures/slits is called the *diffraction*.



# Huygens principle

Huygens's principle is a geometric construction for using knowledge of an earlier wave front to determine the position of a new wave front at some instant.

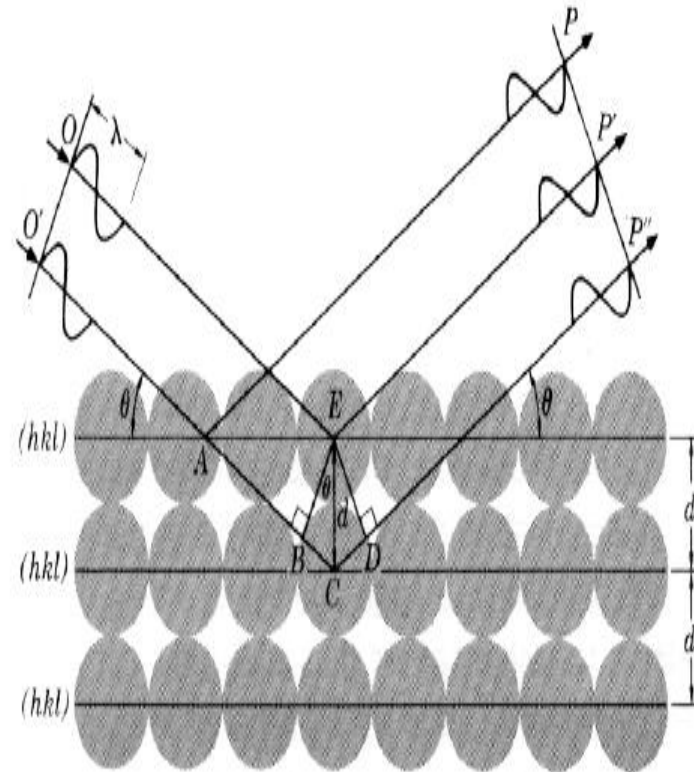
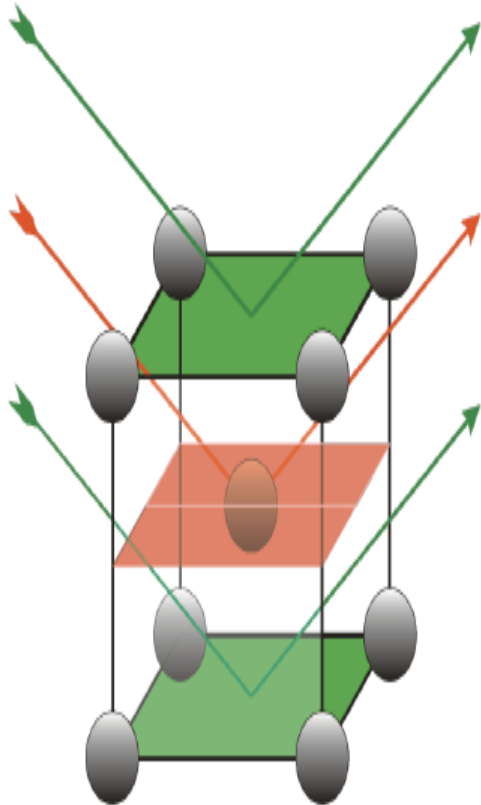


**Figure 35.17** Huygens's construction for (a) a plane wave propagating to the right and (b) a spherical wave propagating to the right.

# Bragg's Law

Incident beams are reflected in phase if the path difference between them equals an integer multiple of the wavelength

$$2d \sin \theta = n\lambda$$



# Structure factor

$\phi = 2\pi(hx' + ky' + lz')$  the *Phase difference* between rays scattered from origin and rays scattered from the atom.

$$F = \frac{\text{amplitude of waves the scattered atom in UC}}{\text{amplitude of waves scattered by free electrons}}$$

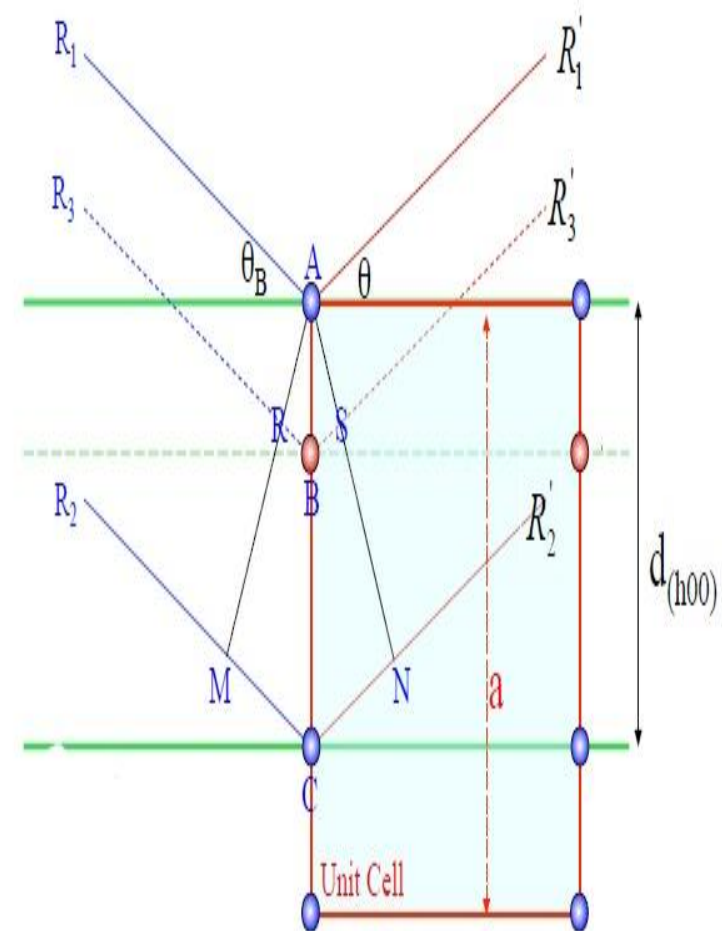
$F = \sum_{j=1}^n f_j e^{i\phi_j}$  for  $j=1, \dots, n$  atoms in the unit cell

For x-rays  $f_j$  is an atomic form factor,  $f_j = f(A)$ .

For neutrons  $f_j$  is a scattering length,  $f_j \neq f(A)$ .

The unit cell scattering factor is called the structure factor.

$$I = |F|^2 \delta(\vec{H}_{hkl} - (\vec{k}_i - \vec{k}_f))$$



# Diffraction of x-rays

**X-ray diffraction is an analytical method used to analyse the material properties like phase composition, structure, texture and many more of powder samples, solid samples and even liquid samples.**

**Wilhelm Conrad Roentgen, his wife's hand.**

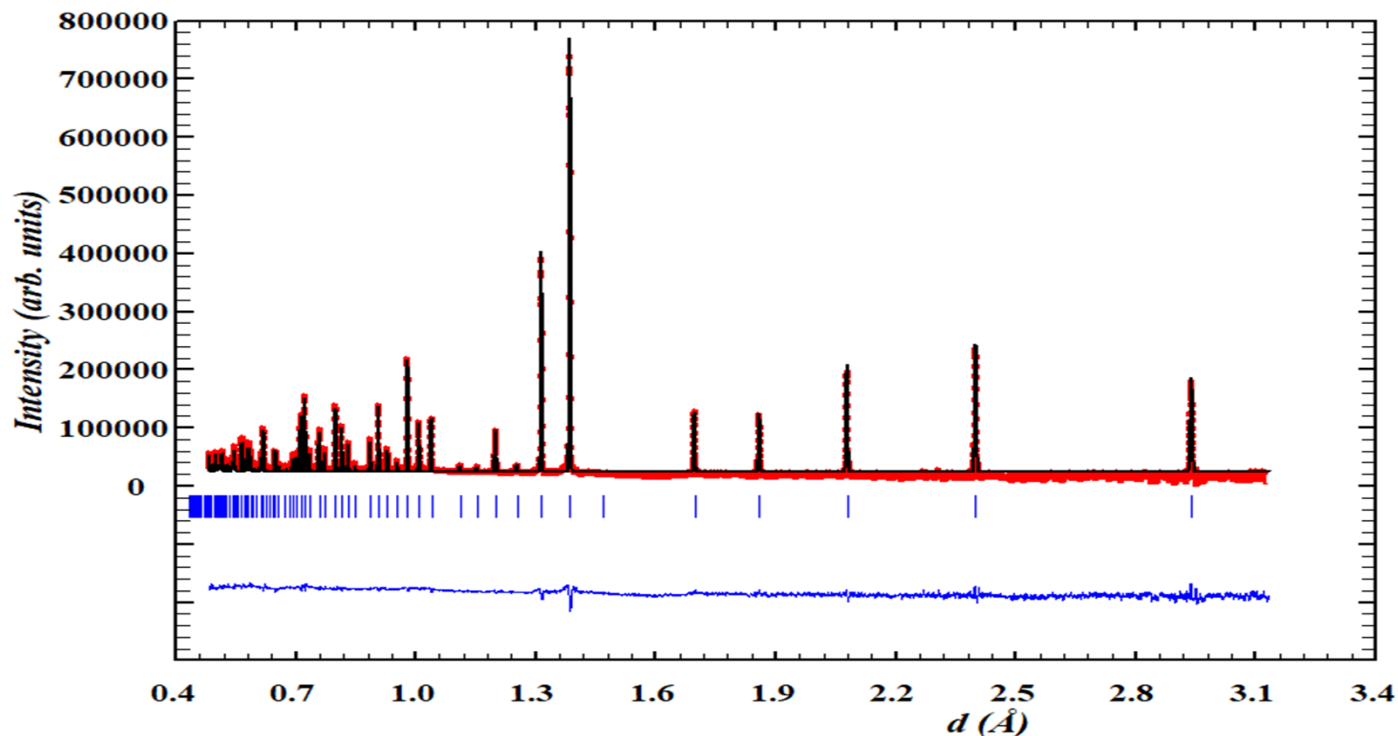


# Powder diffraction

In x-ray powder diffraction the sample consists of an infinitely large number of small crystallites, ideally randomly oriented with respect to each other.

Powder diffractogram is obtained by counting the detected intensities as a function of the angle between the incident and the diffracted beam.

**LAB6 , High Resolution refinement**





A decorative graphic consisting of several parallel white lines of varying thicknesses, slanted diagonally from the bottom-left towards the top-right, set against a solid dark blue background.

# PART II CHARACTERISATION OF NIOBIUM CARBIDE BY X-RAY DIFFRACTION

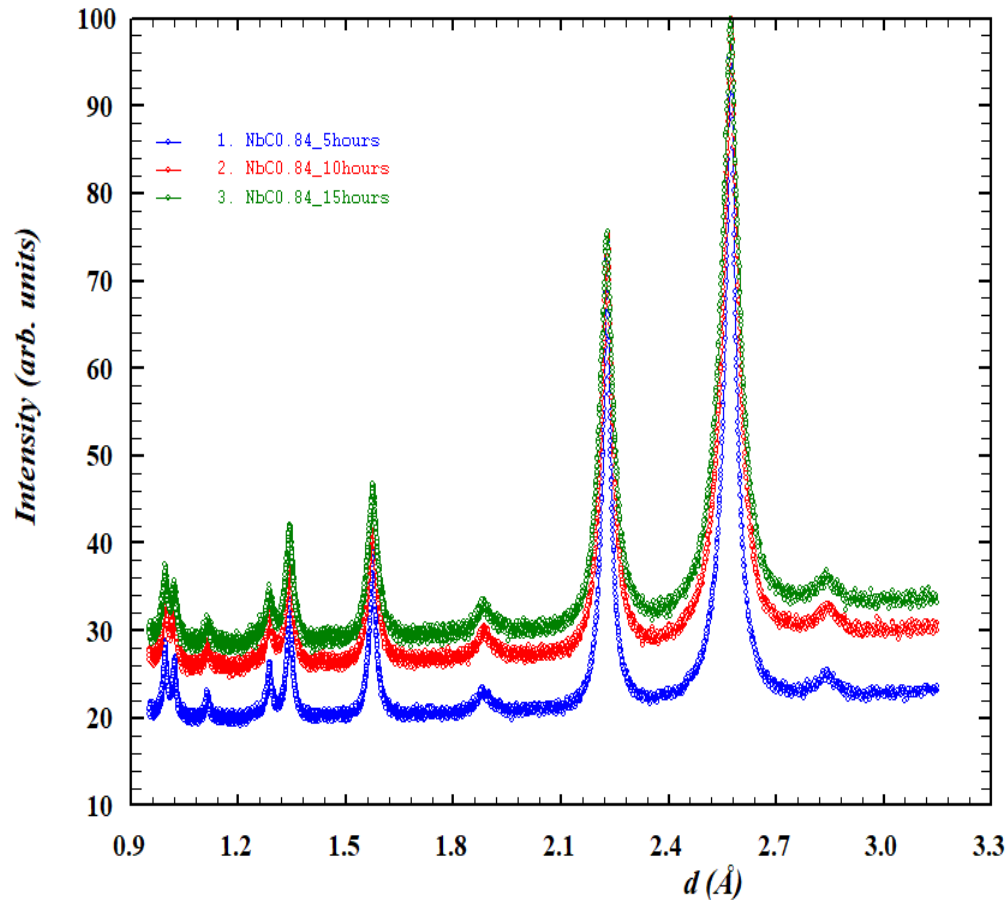
Kudzai Emmanuel Sithole

# Sample and instruments

- The non-stoichiometric powder  $\text{NbC}_{0.84}$  was used
- The powder was milled in a planetary ball mill for 5, 10 and 15 hours
- Panalytical X-ray diffractometer was used to obtain X-ray diffraction spectra

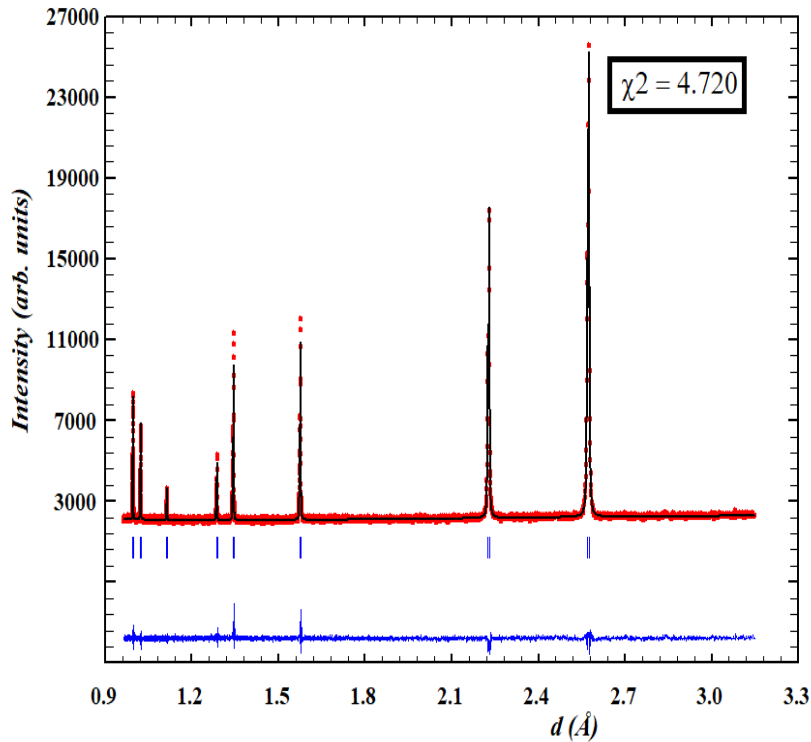


# Comparison of the X-ray diffraction spectra

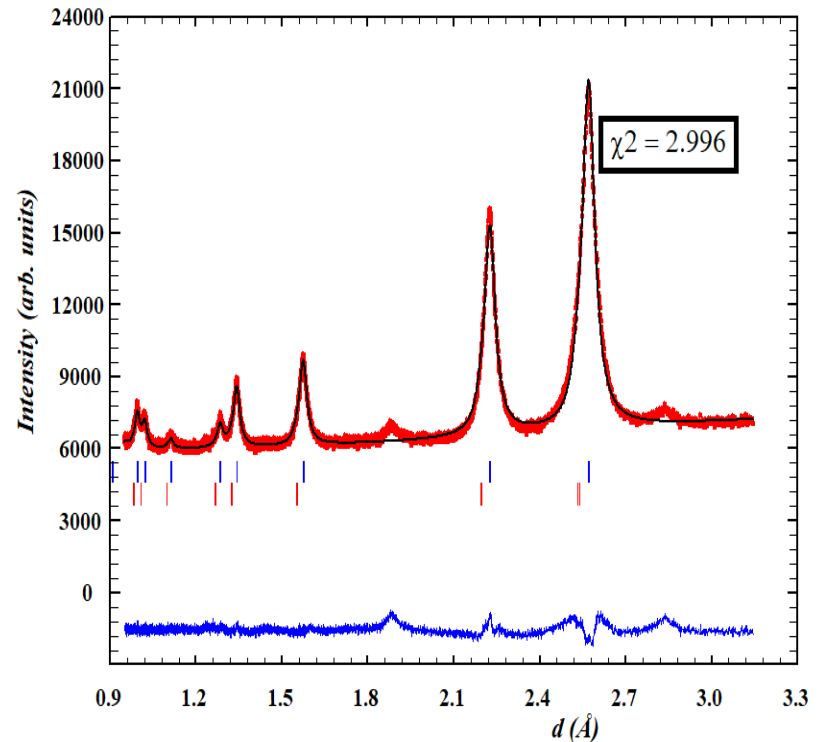


# Refinement of NbC milled for 0 hours and for 15 hours with two phases

NbC 0.84 0 hours (XRD)

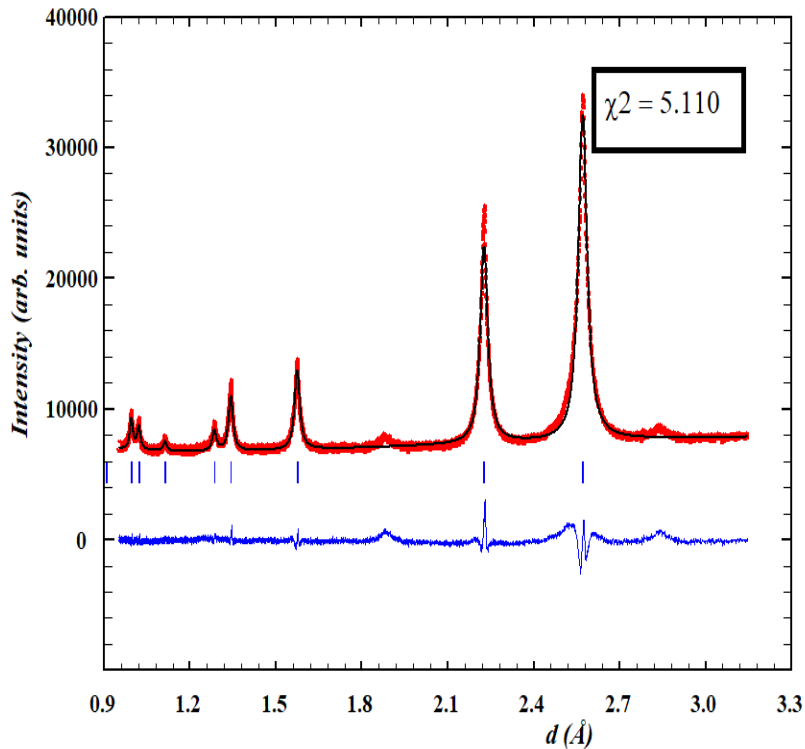


NbC 0.84 15hrs 2 phases XRD

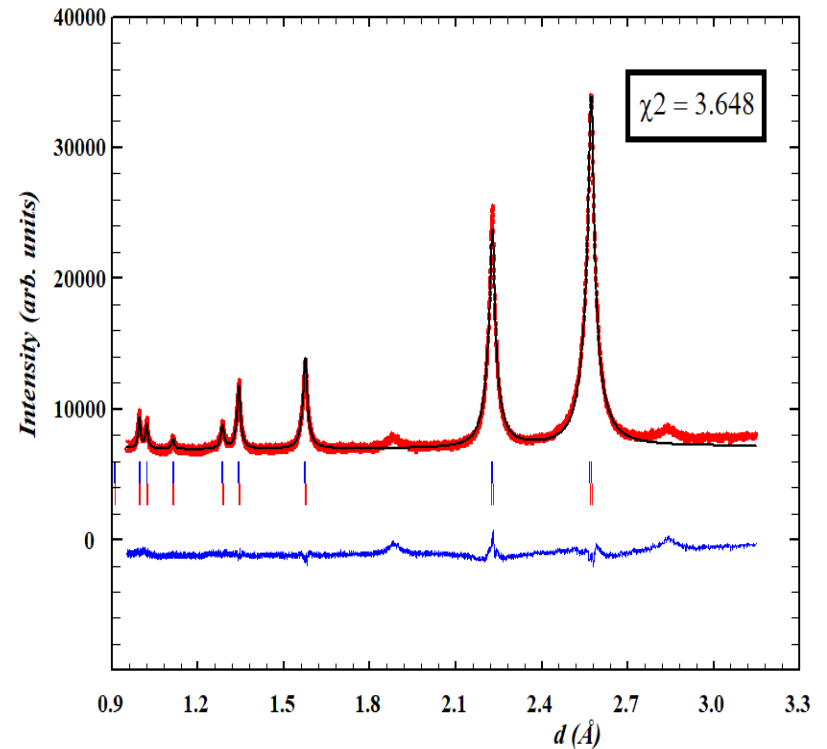


# Refinement of NbC milled for 5 hours considering 1 phase and 2 phases

NbC 0.84 5 hours (XRD)

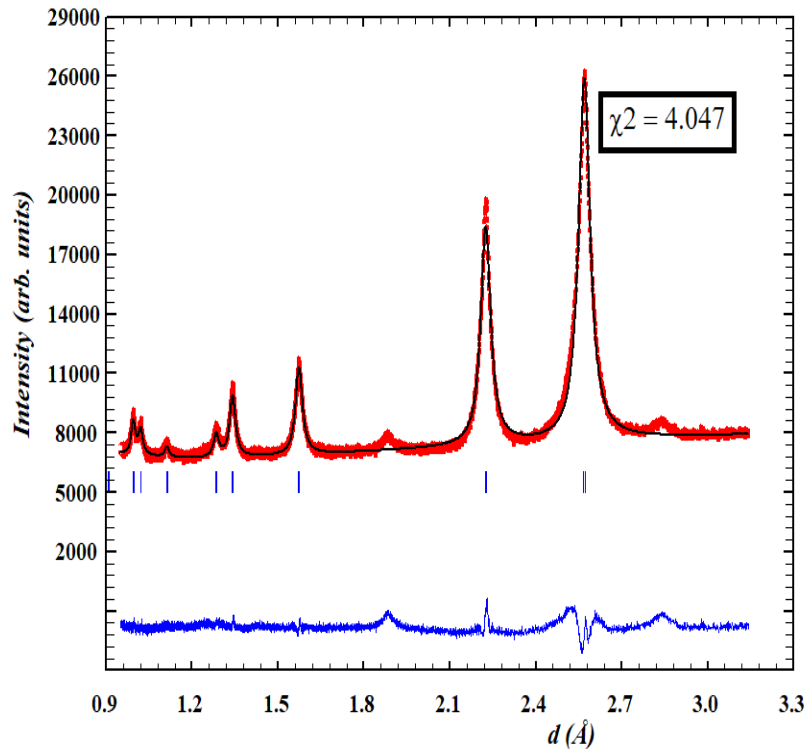


NbC 0.84 5hours (Nano and Micro) XRD

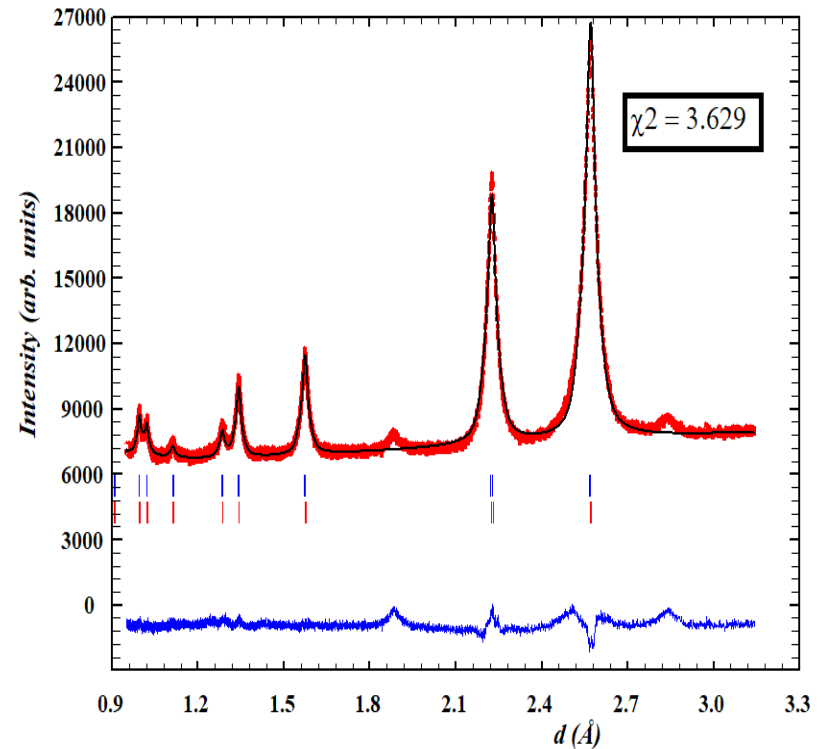


# Refinement of NbC milled for 10 hours considering 1 phase and 2 phases

NbC 0.84 10hours XRD

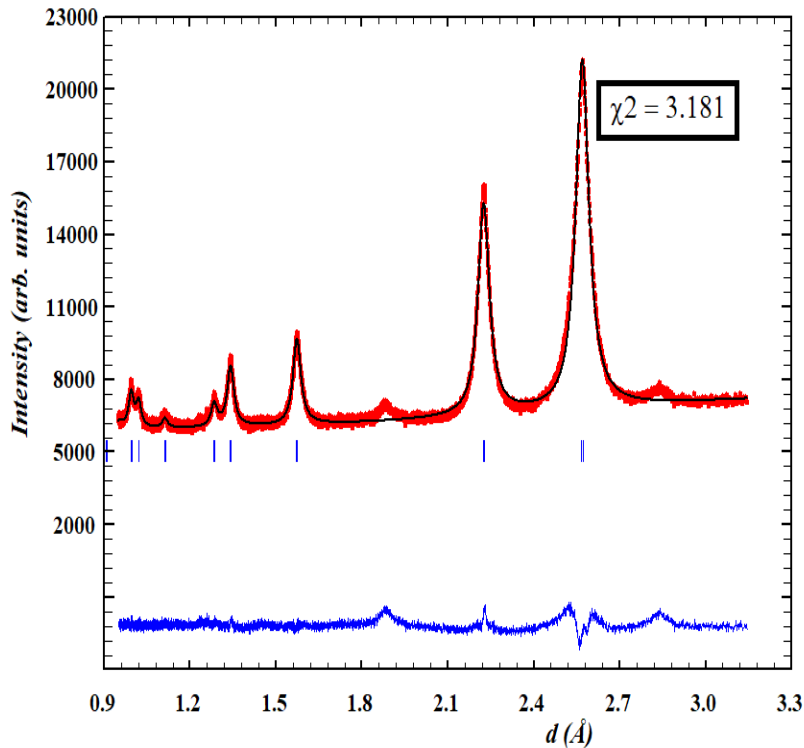


NbC 0.84 for 10hrs with (Nano and Micro) XRD

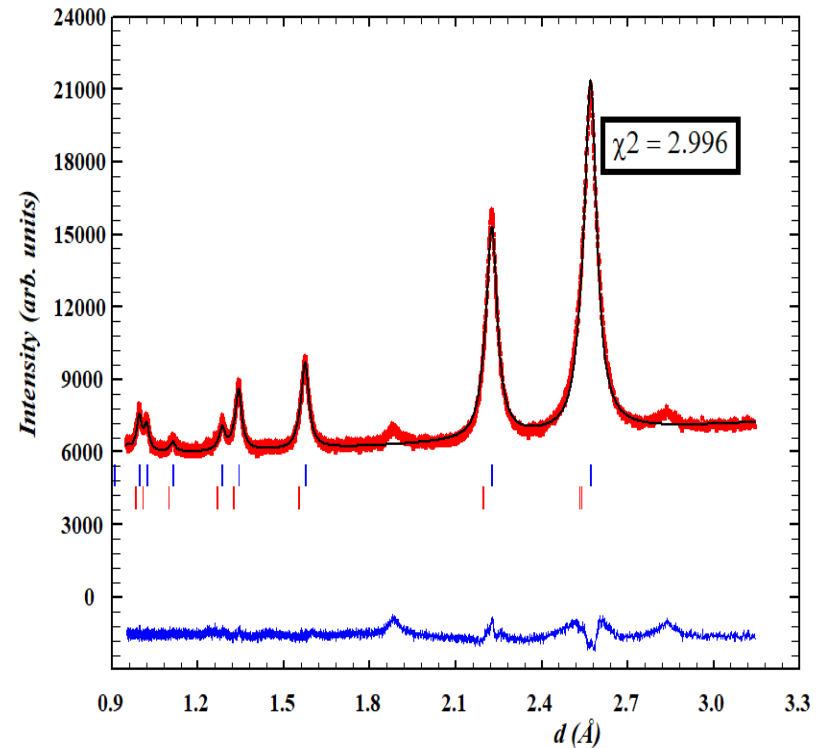


# Refinements of NbC milled for 15 hours considering the 1 and 2 phases respectively

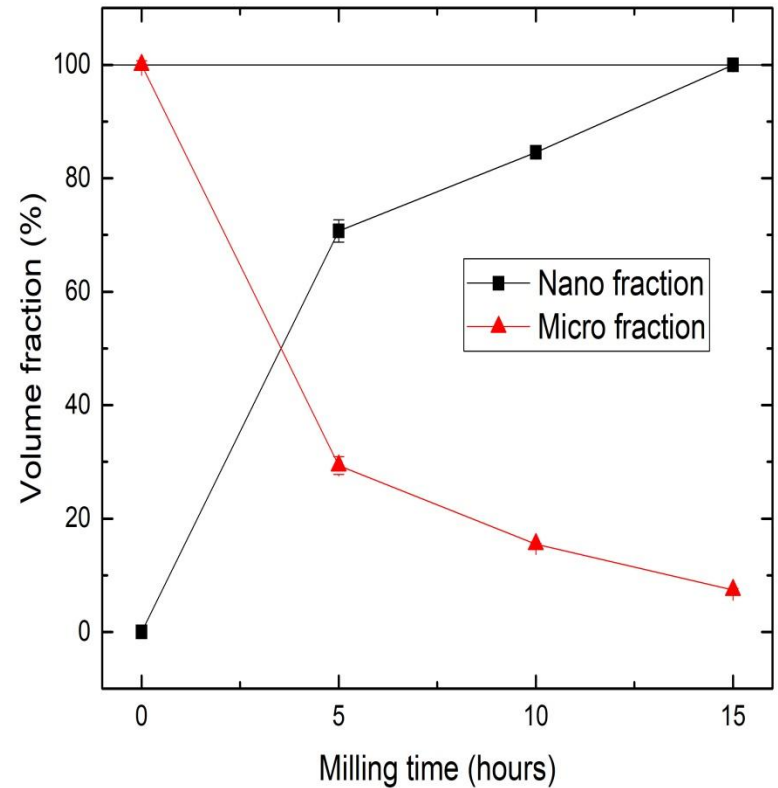
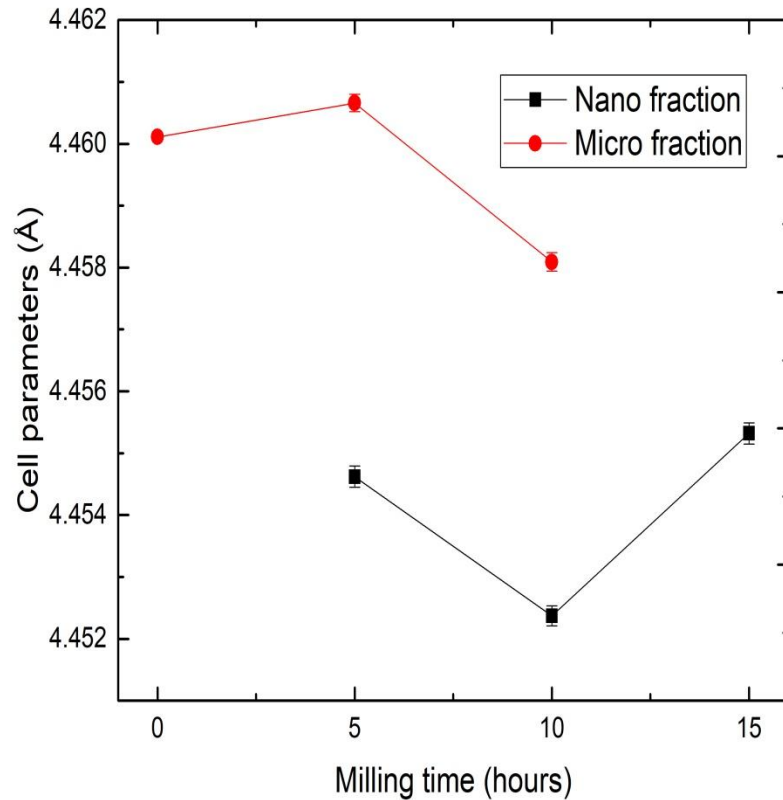
NbC 0.84 15hrs XRD



NbC 0.84 15hrs 2 phases XRD



# Structure parameters obtained from Rietveld refinements



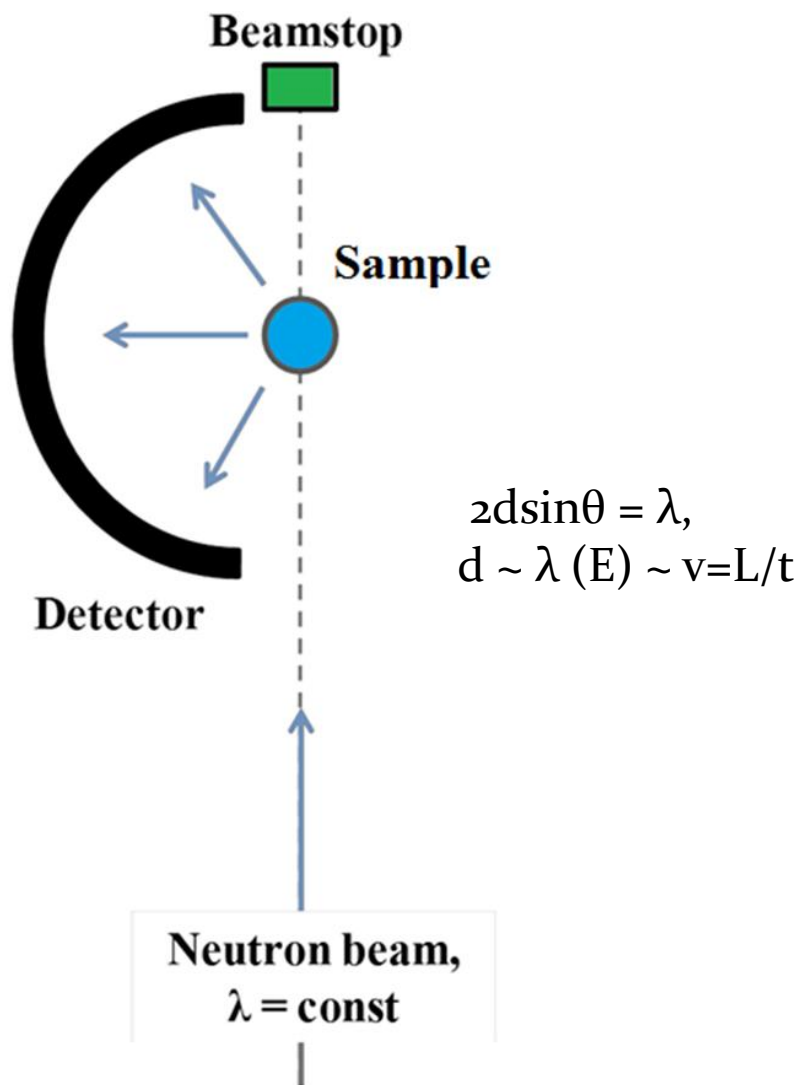


PART III  
NEUTRON SCATTERING  
FOR NIOBIUM CARBIDE

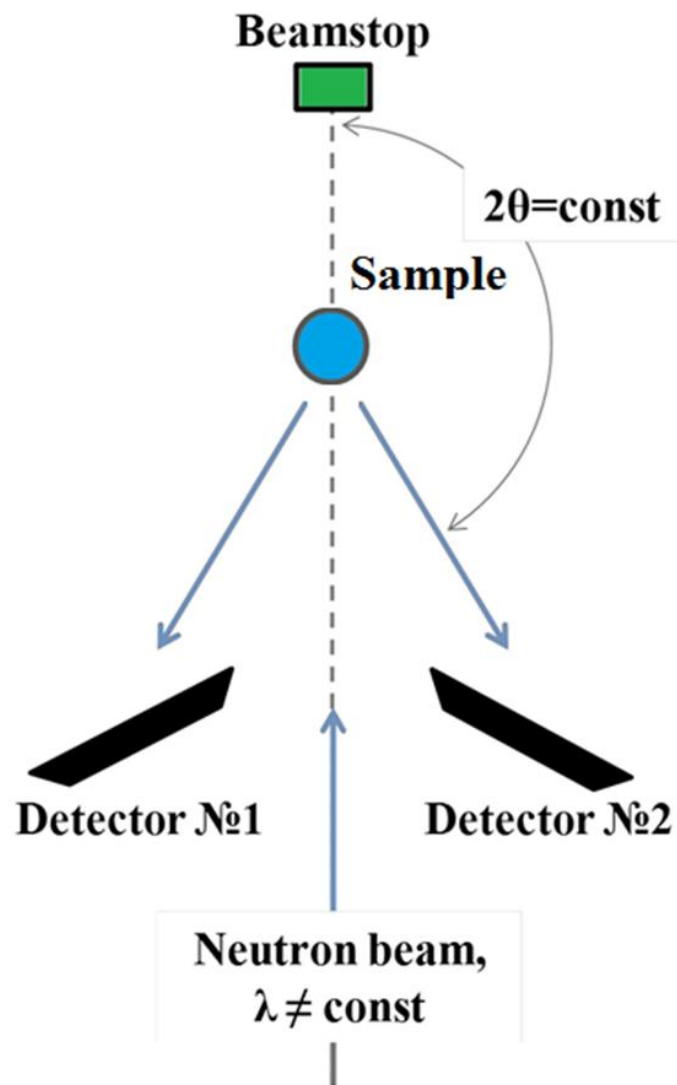
MASHAKA MOLEPO

A series of several parallel white lines of varying thicknesses, slanted diagonally from the bottom left towards the top right, crossing the right side of the text area.

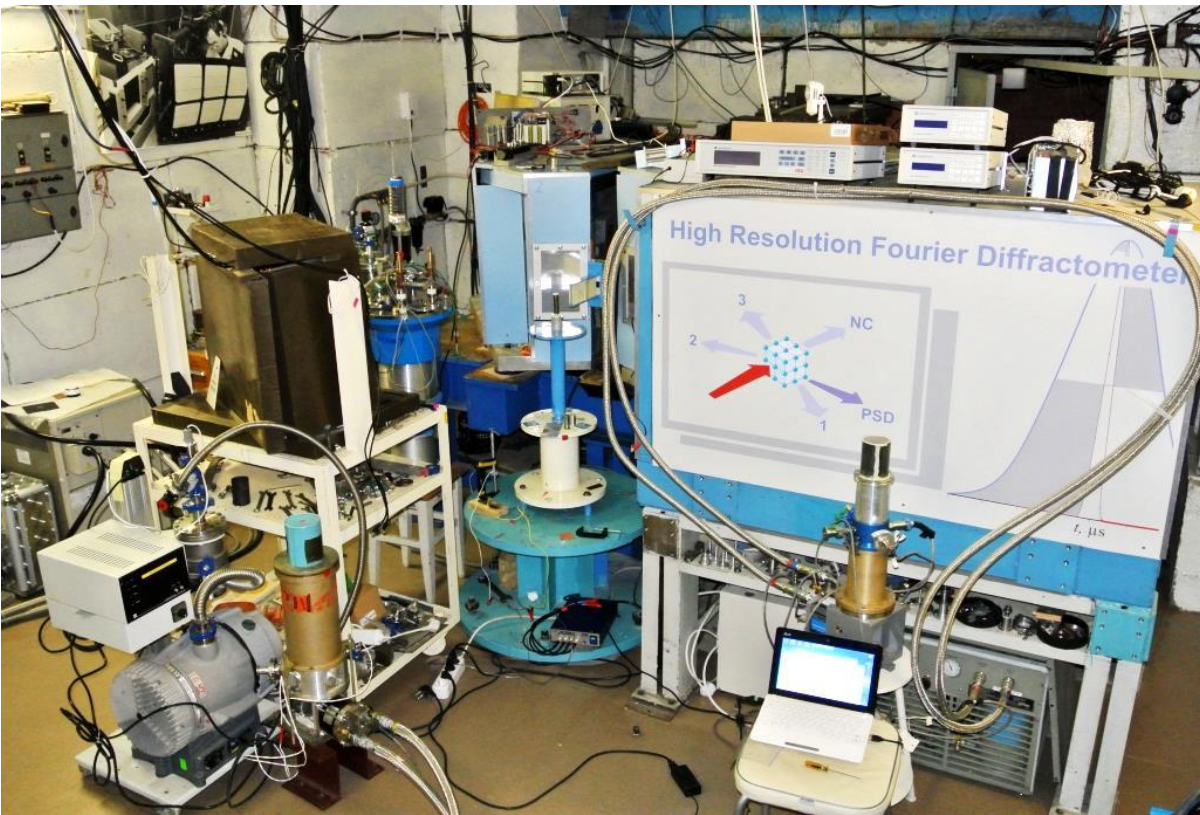
## Conventional geometry



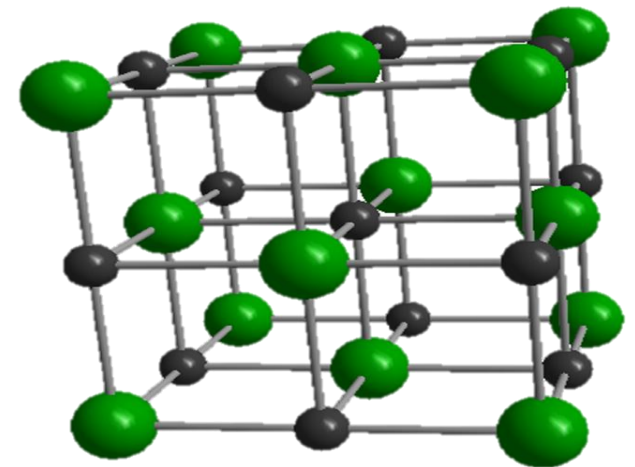
## Time-of-flight geometry



# Experimental Setup and Sample

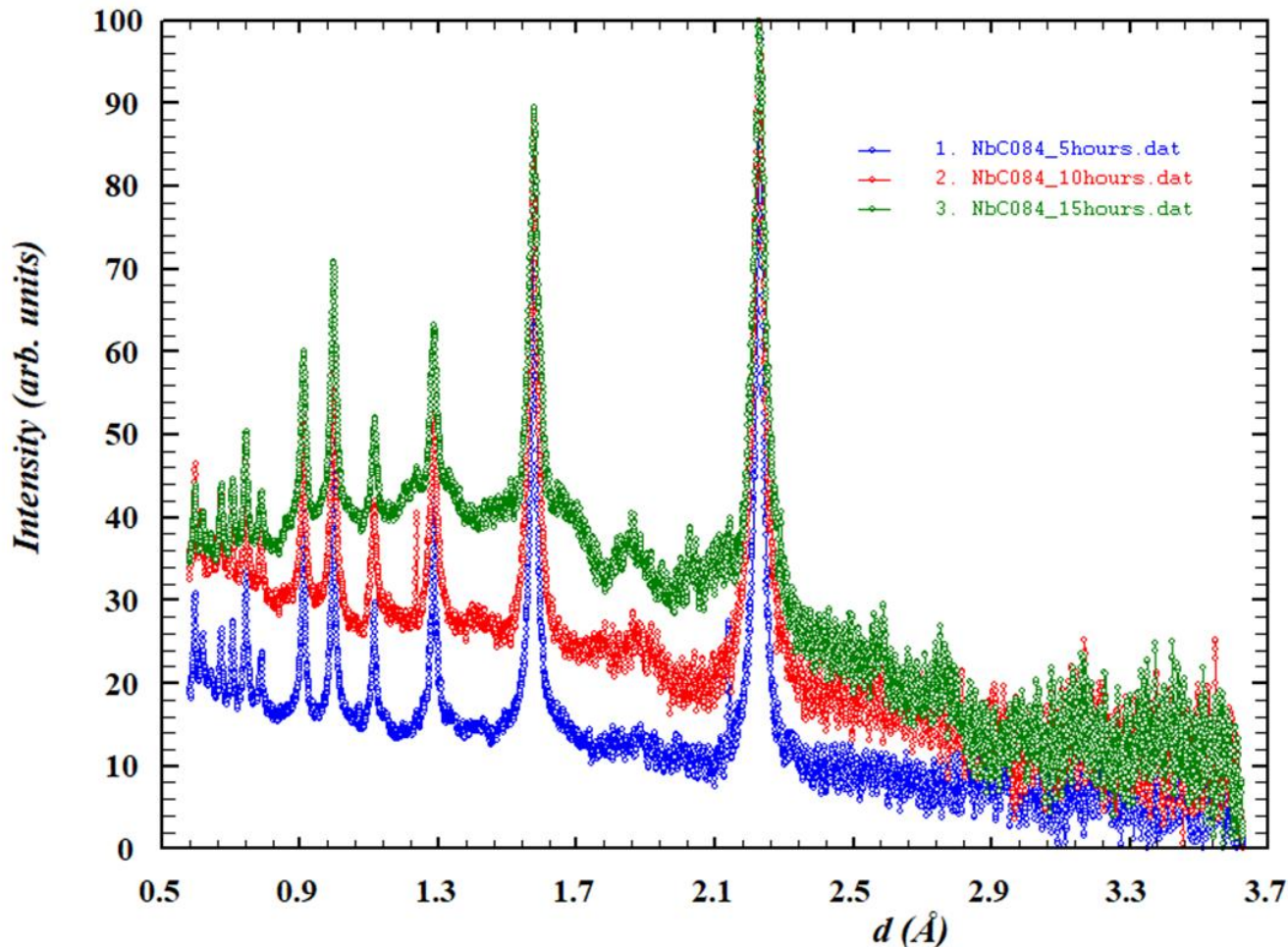


Time-of-flight high resolution fourier diffractometer installed at IBR-2 reactor. Resolution  $\sim 0.001$ , almost independent of  $d$  spacing.



Niobium Carbide  
 $\text{NbC}_{0.84}$

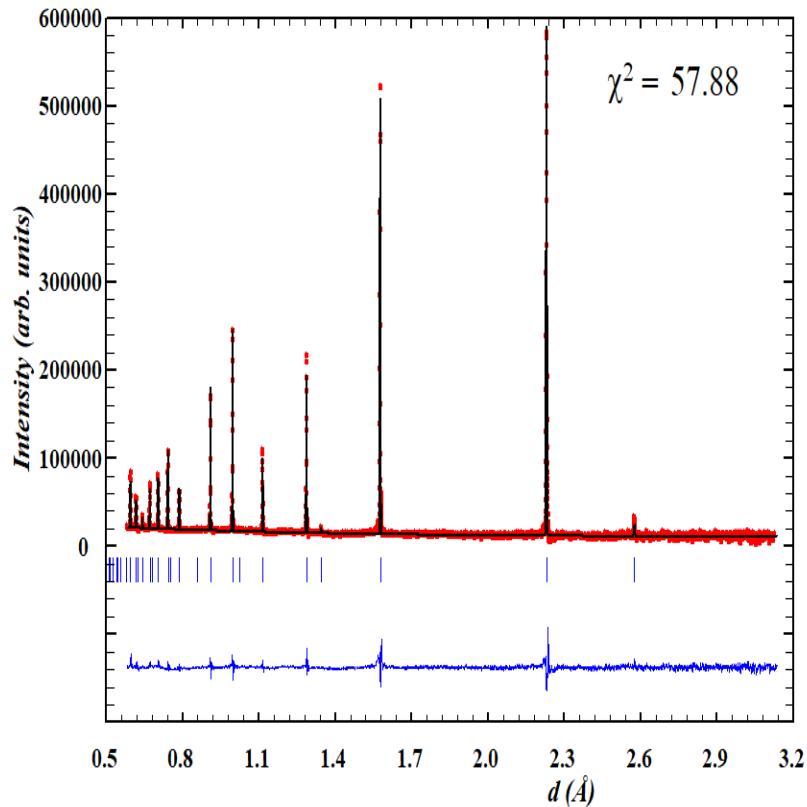
# Comparison of diffraction spectra



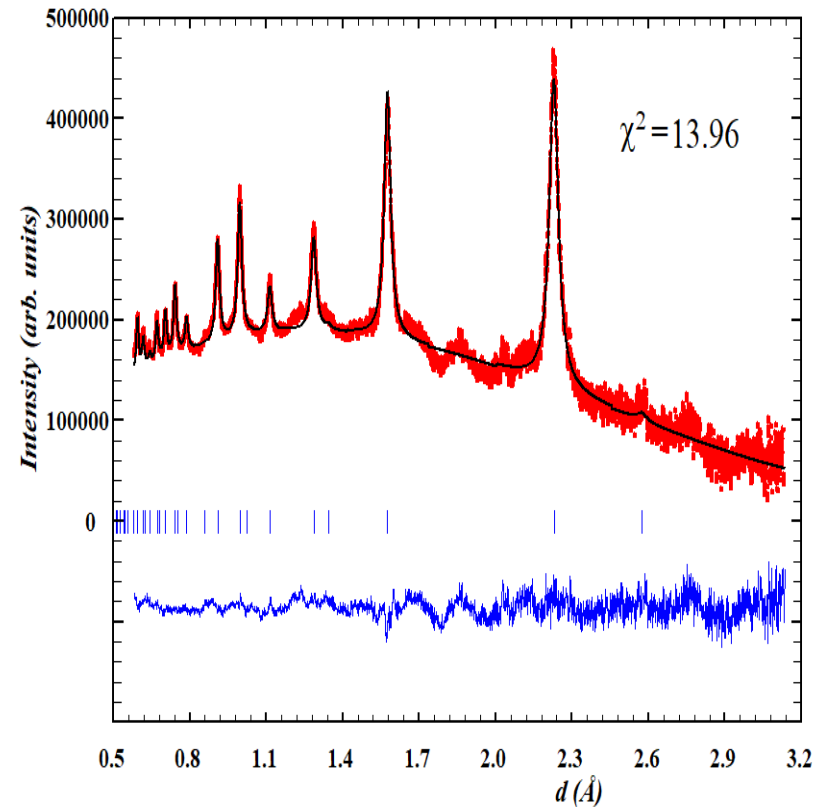
- ❖ In  $\text{NbC}_{0.84}$ , defects only occur in C substructure.
- ❖ Neutrons scatter the same on Nb and C atoms while X-rays scatter mostly on Nb.
- ❖ BAD : its hard to do refinement compared to X-ray.
- ❖ GOOD : It gives more information about the sample.

# Refinement of NbC milled for 5 hours in 1 phase and 2 phases

NbC<sub>0.84</sub>, 0 hours, 1 Phase refinement

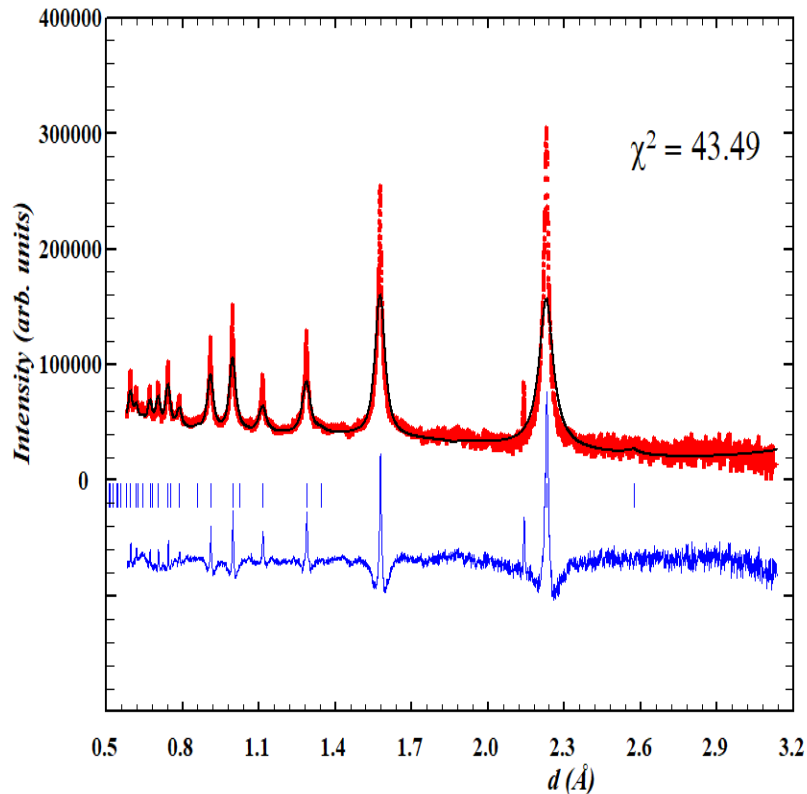


NbC<sub>0.84</sub>, 15 hours, 1 Phase refinement

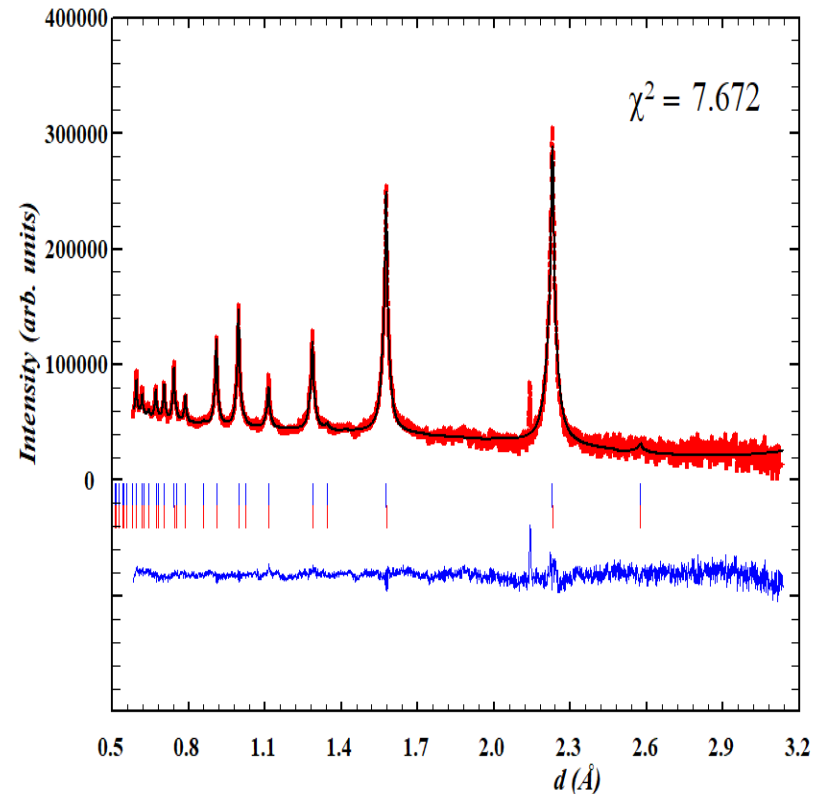


# Refinement of NbC milled for 5 hours in 1 phase and 2 phases

NbC0\_84 , 5 hours , 1 Phase refinement

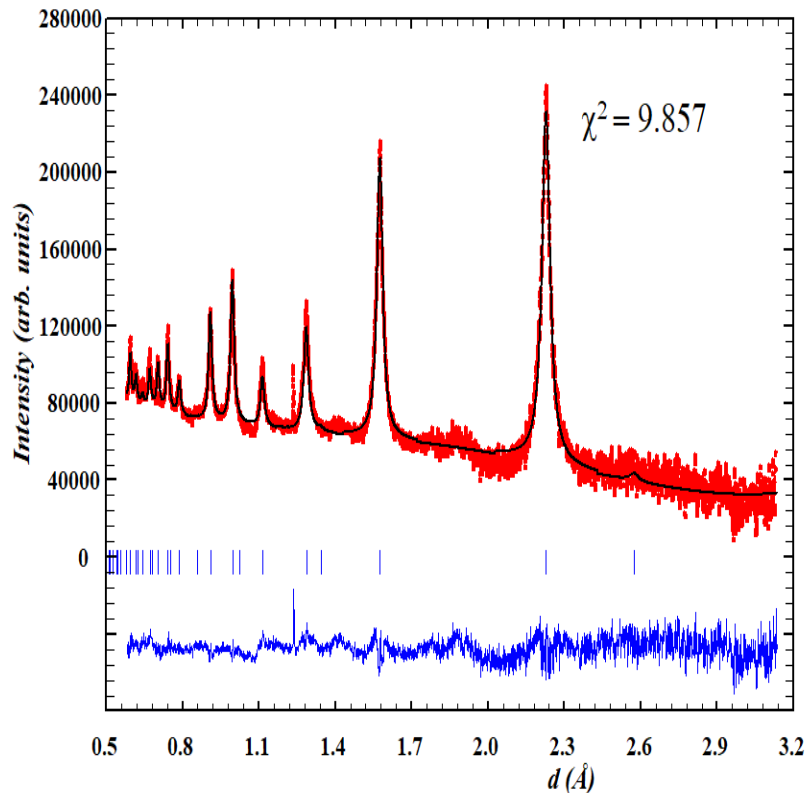


NbC0\_84 , 5 hours , 2 Phase refinement

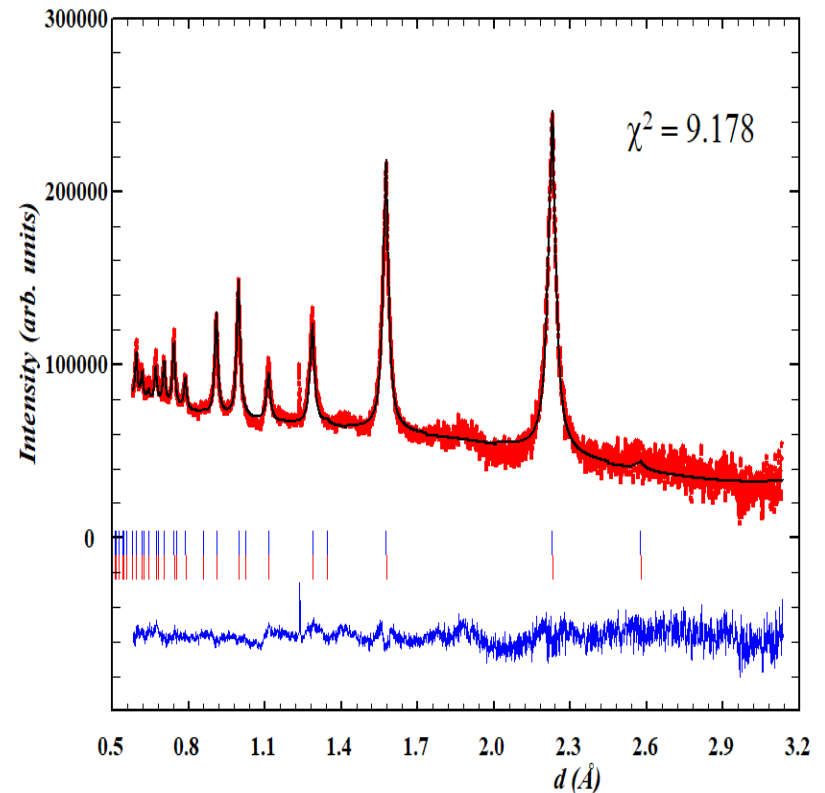


# Refinement of NbC milled for 10 hours in 1 phase and 2 phases

NbC0\_84, 10hours, 1 Phase refinement

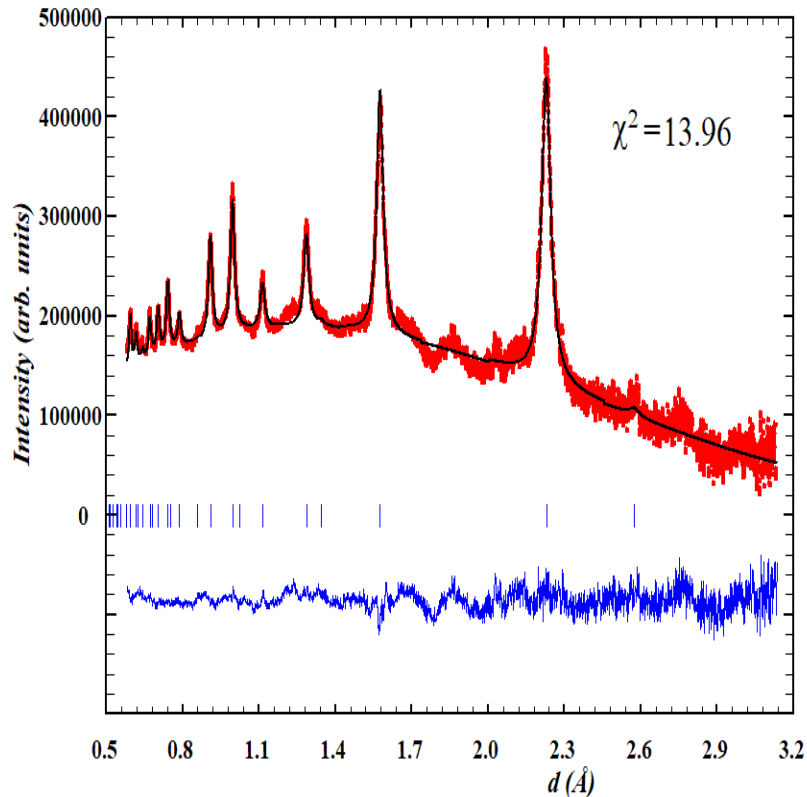


NbC0\_84, 10 hours, 2 Phase refinement

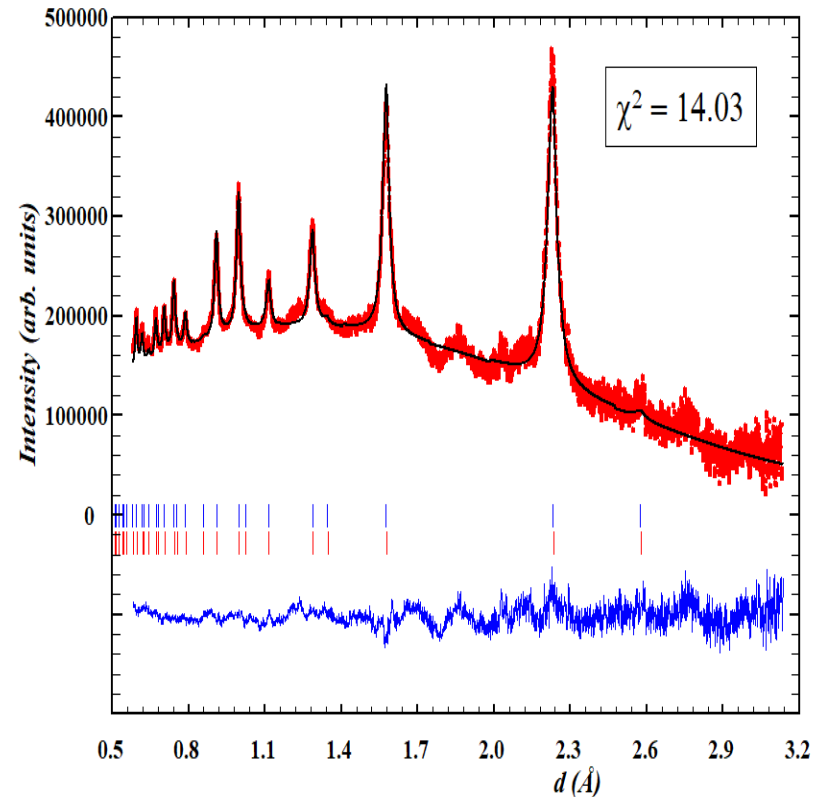


# Refinements NbC milled for 15 hours for 1 and 2 phases

NbC<sub>0.84</sub>, 15hours, 1 Phase refinement

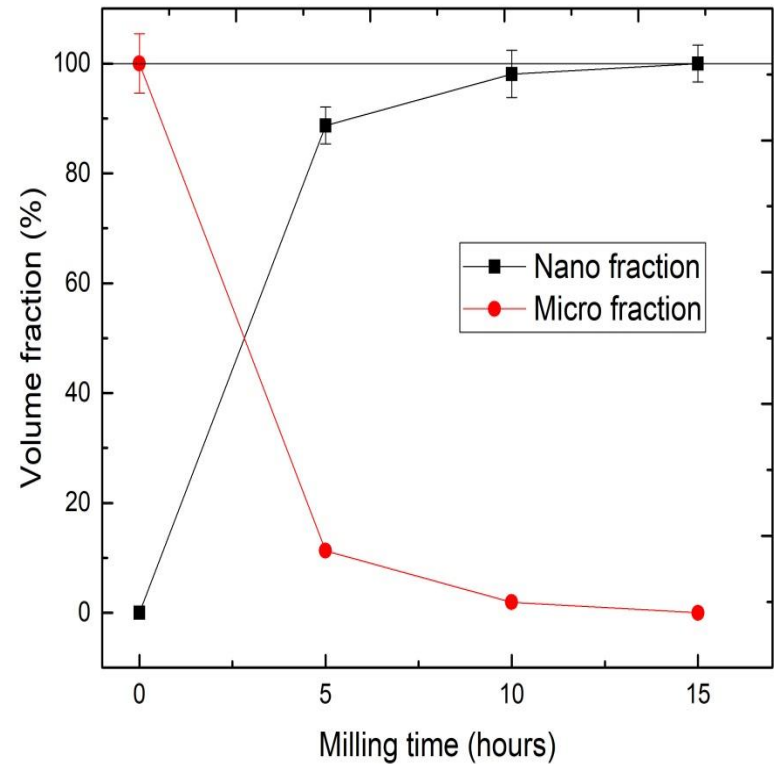
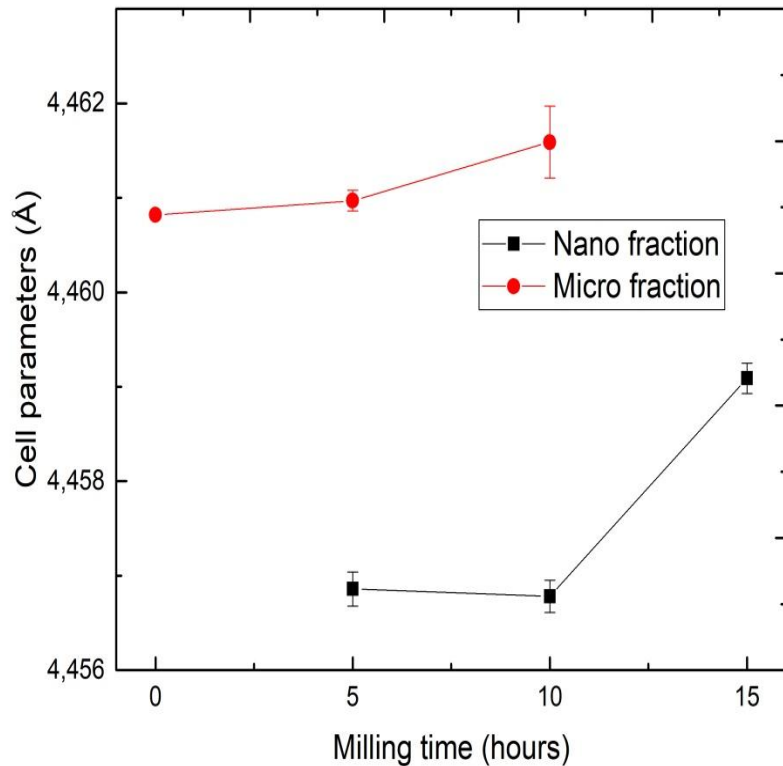


NbC<sub>0.84</sub>, 15 hours milling, 2 phase refinement





# Structure parameters obtained from Rietveld refinements





**Thank you for attention!**

**Spasibo za vnimanie!**

**Ndo livhuwa chifhinga chavho!**